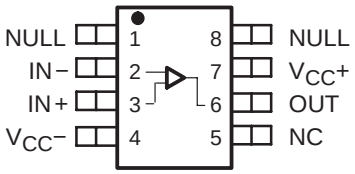
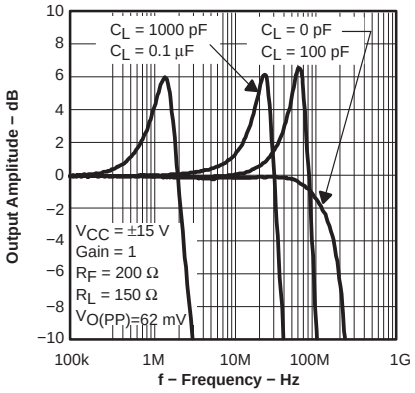
- **Qualified for Automotive Applications**
- **C-Stable Amplifier Drives Any Capacitive Load**
- **High Speed**
  - **165 MHz Bandwidth (−3 dB); C_L = 0 pF**
  - **100 MHz Bandwidth (−3 dB); C_L = 100 pF**
  - **35 MHz Bandwidth (−3 dB); C_L = 1000 pF**
  - **400 V/μs Slew Rate**
- **Unity Gain Stable**
- **High Output Drive, I_O = 100 mA (typ)**
- **Low Distortion**
  - **THD = −75 dBc (f = 1 MHz, R_L = 150 Ω)**
  - **THD = −89 dBc (f = 1 MHz, R_L = 1 kΩ)**
- **Wide Range of Power Supplies**
  - **V_{CC} = ±5 V to ±15 V**
- **Evaluation Module Available**

THS4041
D PACKAGE
(TOP VIEW)



NC − No internal connection

OUTPUT AMPLITUDE
vs
FREQUENCY



description/ordering information

The THS4041 is a single, high-speed voltage feedback amplifier capable of driving any capacitive load. This makes it ideal for a wide range of applications including driving video lines or buffering ADCs. The device features high 165-MHz bandwidth and 400-V/μs slew rate. The THS4041 is stable at all gains for both inverting and noninverting configurations. For video applications, the THS4041 offers excellent video performance with 0.01% differential gain error and 0.01° differential phase error. This amplifier can drive up to 100 mA into a 20-Ω load and operate off power supplies ranging from ±5 V to ±15 V.

ORDERING INFORMATION†

T_A	NUMBER OF CHANNELS	PACKAGE‡		ORDERABLE PART NUMBER	TOP-SIDE MARKING
−40°C to 85°C	1	SOIC (D)	Tape and Reel	THS4041IDRQ1	4041Q1

† For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at http://www.ti.com.

‡ Package drawings, thermal data, and symbolization are available at http://www.ti.com/packaging.

CAUTION: The THS4041 provides ESD protection circuitry. However, permanent damage can still occur if this device is subjected to high-energy electrostatic discharges. Proper ESD precautions are recommended to avoid any performance degradation or loss of functionality.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PowerPAD is a trademark of Texas Insruments Incorporated.

functional block diagram

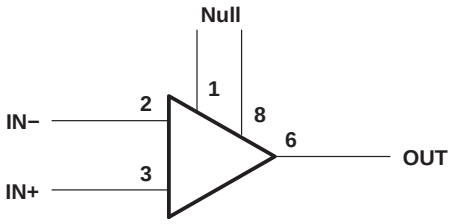


Figure 1. THS4041 − Single Channel

absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage, V_{CC} . . . . . ±16.5 V
Input voltage, V_I . . . . . $\pm V_{CC}$
Output current, I_O . . . . . 150 mA
Differential input voltage, V_{IO} . . . . . ±4 V
Maximum junction temperature, T_J (see Figure 2) . . . . . 150°C
Package thermal impedance, θ_{JA} (see Note 1) . . . . . 215°C/W
Operating free-air temperature, T_A: I-suffix . . . . . −40°C to 85°C
Storage temperature, T_{stg} . . . . . −65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 3 seconds . . . . . 300°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: This data was taken using the JEDEC standard Low-K test PCB. For the JEDEC proposed High-K test PCB, the θ_{JA} is 126°C/W.

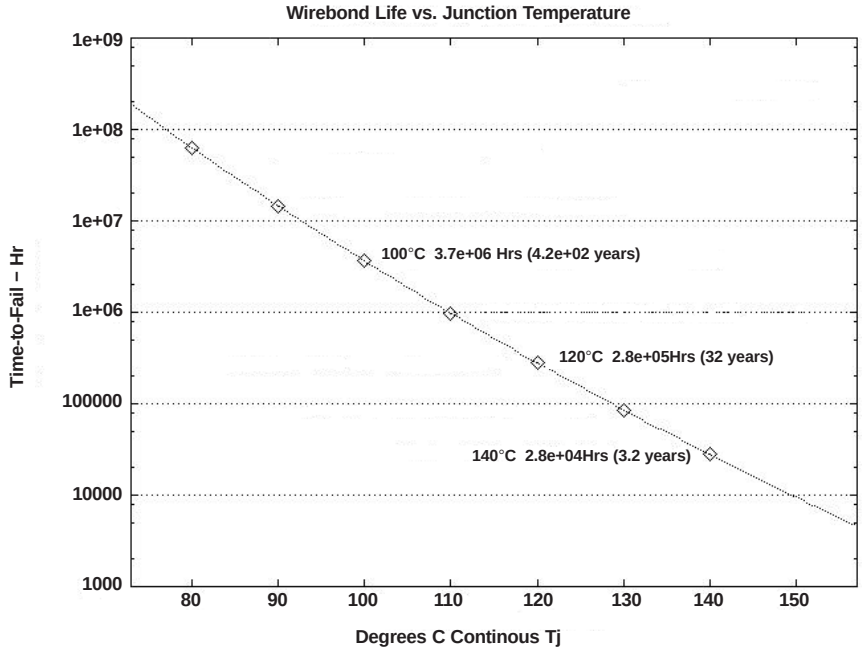


Figure 2. Estimated Wirebond Life

recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V_{CC+} and V_{CC-}	Dual supply	±4.5		±16	V
	Single supply	9		32	
Operating free-air temperature, T_A	I-suffix	−40		85	°C

electrical characteristics at T_A = 25°C, V_{CC} = ±15 V, R_L = 150 Ω (unless otherwise noted)

dynamic performance

PARAMETER		TEST CONDITIONS†			MIN	TYP	MAX	UNIT
BW	Dynamic performance small-signal bandwidth (−3 dB)	V_{CC} = ±15 V	R_f = 200 Ω	Gain = 1		165		MHz
		V_{CC} = ±5 V	R_f = 200 Ω	Gain = 1		150		MHz
		V_{CC} = ±15 V	R_f = 1.3 kΩ	Gain = 2		60		MHz
		V_{CC} = ±5 V	R_f = 1.3 kΩ	Gain = 2		60		MHz
	Bandwidth for 0.1 dB flatness	V_{CC} = ±15 V	R_f = 200 Ω	Gain = 1		45		MHz
		V_{CC} = ±5 V	R_f = 200 Ω	Gain = 1		45		MHz
	Full power bandwidth§	$V_{O(pp)}$ = 20 V,	V_{CC} = ±15 V			6.3		MHz
		$V_{O(pp)}$ = 5 V,	V_{CC} = ±5 V			20		MHz
SR	Slew rate‡	V_{CC} = ±15 V,	20-V step,	Gain = 5		400		V/µs
		V_{CC} = ±5 V,	5-V step,	Gain = −1		325		V/µs
t_s	Settling time to 0.1%	V_{CC} = ±15 V,	5-V step	Gain = −1		120		ns
		V_{CC} = ±5 V,	2-V step	Gain = −1		120		ns
	Settling time to 0.01%	V_{CC} = ±15 V,	5-V step	Gain = −1		250		ns
		V_{CC} = ±5 V,	2-V step	Gain = −1		280		ns

† Full range = −40°C to 85°C for I suffix
‡ Slew rate is measured from an output level range of 25% to 75%.
§ Full power bandwidth = slew rate / 2 π $V_{O(Peak)}$.

noise/distortion performance

PARAMETER		TEST CONDITIONS†			MIN	TYP	MAX	UNIT
THD	Total harmonic distortion	$V_{O(pp)}$ = 2 V, f = 1 MHz, Gain = 2	V_{CC} = ±15 V	R_L = 150 Ω		−75		dBc
				R_L = 1 kΩ		−89		dBc
			V_{CC} = ±5 V	R_L = 150 Ω		−75		dBc
				R_L = 1 kΩ		−86		dBc
V_n	Input voltage noise	V_{CC} = ±5 V or ±15 V,	f = 10 kHz			14		nV/√Hz
I_n	Input current noise	V_{CC} = ±5 V or ±15 V,	f = 10 kHz			0.9		pA/√Hz
	Differential gain error	Gain = 2, 40 IRE modulation,	NTSC, ±100 IRE ramp	V_{CC} = ±15 V		0.01%		
				V_{CC} = ±5 V		0.01%		
	Differential phase error	Gain = 2, 40 IRE modulation,	NTSC, ±100 IRE ramp	V_{CC} = ±15 V		0.01°		
				V_{CC} = ±5 V		0.02°		

† Full range = −40°C to 85°C for I suffix

electrical characteristics at T_A = 25°C, V_{CC} = ±15 V, R_L = 150 Ω (unless otherwise noted) (continued)

dc performance

PARAMETER		TEST CONDITIONS†			MIN	TYP	MAX	UNIT
	Open loop gain	V_{CC} = ±15 V, V_O = ±10 V, R_L = 1 kΩ		T_A = 25°C	74	80		dB
				T_A = full range	69			
		V_{CC} = ±5 V, V_O = ±2.5 V, R_L = 250 Ω		T_A = 25°C	69	76		
				T_A = full range	66			
V_{OS}	Input offset voltage	V_{CC} = ±5 V or ±15 V		T_A = 25°C		2.5	10	mV
				T_A = full range			13	
	Offset voltage drift	V_{CC} = ±5 V or ±15 V		T_A = full range		10		µV/°C
I_{IB}	Input bias current	V_{CC} = ±5 V or ±15 V		T_A = 25°C		2.5	6	µA
				T_A = full range			8	
I_{OS}	Input offset current	V_{CC} = ±5 V or ±15 V		T_A = 25°C		35	250	nA
				T_A = full range			400	
	Offset current drift	T_A = full range				0.3		nA/°C

† Full range = −40°C to 85°C for I suffix

input characteristics

PARAMETER		TEST CONDITIONS†			MIN	TYP	MAX	UNIT
V_{ICR}	Common-mode input voltage range	V_{CC} = ±15 V			±13.8	±14.3		V
		V_{CC} = ±5 V			±3.8	±4.3		
CMRR	Common mode rejection ratio	V_{CC} = ±15 V,	V_{ICR} = ±12 V	T_A = full range	70	90		dB
		V_{CC} = ±5 V,	V_{ICR} = ±2.5 V		80	100		
r_i	Input resistance					1		MΩ
C_i	Input capacitance					1.5		pF

† Full range = −40°C to 85°C for I suffix

electrical characteristics at T_A = 25°C, V_{CC} = ±15 V, R_L = 150 Ω (unless otherwise noted) (continued)

output characteristics

PARAMETER		TEST CONDITIONS†		MIN	TYP	MAX	UNIT
V_O	Output voltage swing	V_{CC} = ±15 V	R_L = 250 Ω	±11.5	±13		V
		V_{CC} = ±5 V	R_L = 150 Ω	±3.2	±3.5		
		V_{CC} = ±15 V	R_L = 1 kΩ	±13	±13.6		V
		V_{CC} = ±5 V		±3.5	±3.8		
I_O	Output current‡	V_{CC} = ±15 V	R_L = 20 Ω	80	100		mA
		V_{CC} = ±5 V		50	65		
I_{SC}	Short-circuit current‡	V_{CC} = ±15 V			150		mA
R_O	Output resistance	Open loop			13		Ω

† Full range = −40°C to 85°C for I suffix

‡ Observe power dissipation ratings to keep the junction temperature below the absolute maximum rating when the output is heavily loaded or shorted. See the *absolute maximum ratings* section of this data sheet for more information.

power supply

PARAMETER		TEST CONDITIONS†		MIN	TYP	MAX	UNIT
V_{CC}	Supply voltage operating range	Dual supply		±4.5		±16.5	V
		Single supply		9		33	
I_{CC}	Supply current (per amplifier)	V_{CC} = ±15 V	T_A = 25°C		8	9.5	mA
			T_A = full range			11	
		V_{CC} = ±5 V	T_A = 25°C		7	8.5	
			T_A = full range			10	
PSRR	Power supply rejection ratio	V_{CC} = ±5 V or ±15 V	T_A = 25°C	75	84		dB
			T_A = full range	70			

† Full range = −40°C to 85°C for I suffix

TYPICAL CHARACTERISTICS

OPEN LOOP GAIN AND PHASE RESPONSE vs FREQUENCY

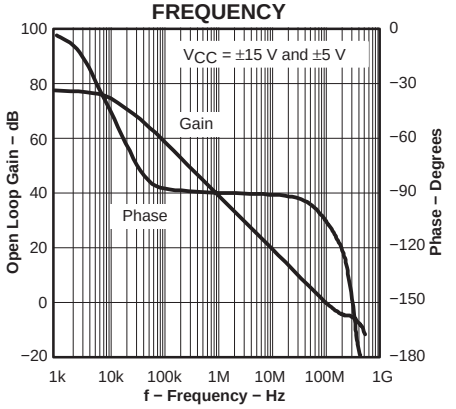


Figure 3

OUTPUT AMPLITUDE vs FREQUENCY

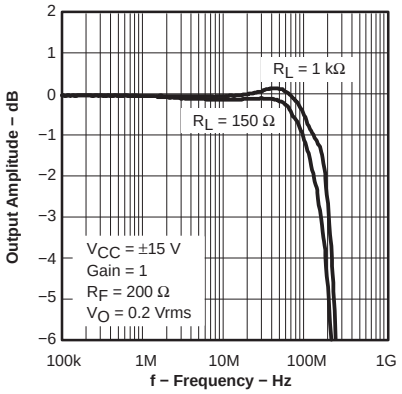


Figure 4

OUTPUT AMPLITUDE vs FREQUENCY

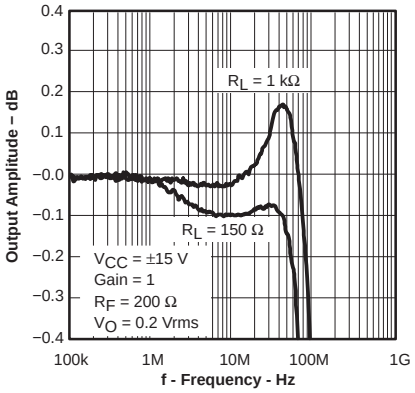


Figure 5

OUTPUT AMPLITUDE vs FREQUENCY

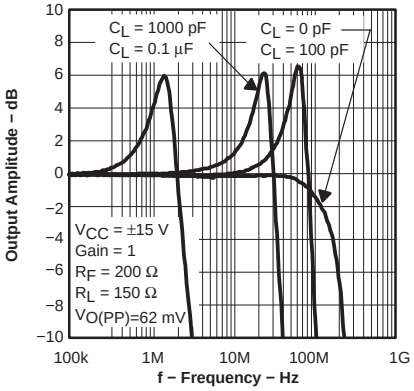


Figure 6

OUTPUT AMPLITUDE vs FREQUENCY

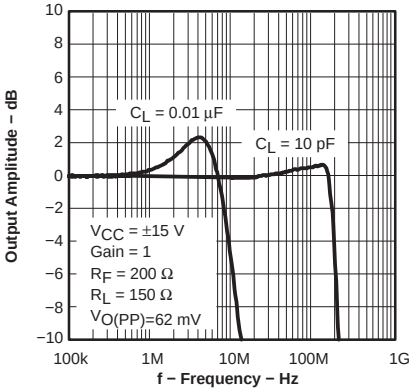


Figure 7

OUTPUT AMPLITUDE vs FREQUENCY

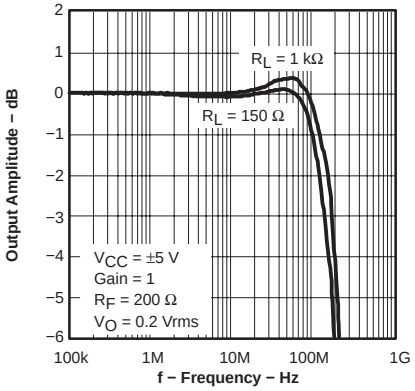


Figure 8

OUTPUT AMPLITUDE vs FREQUENCY

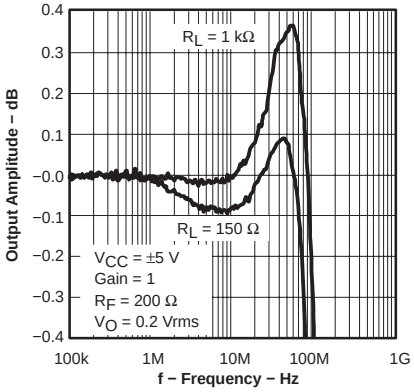


Figure 9

OUTPUT AMPLITUDE vs FREQUENCY

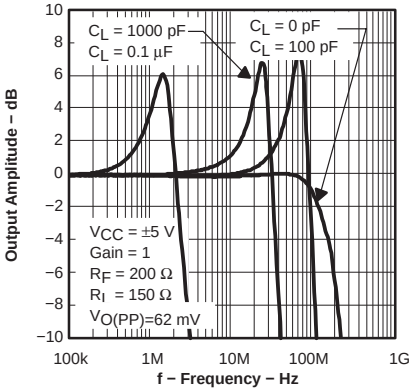


Figure 10

OUTPUT AMPLITUDE vs FREQUENCY

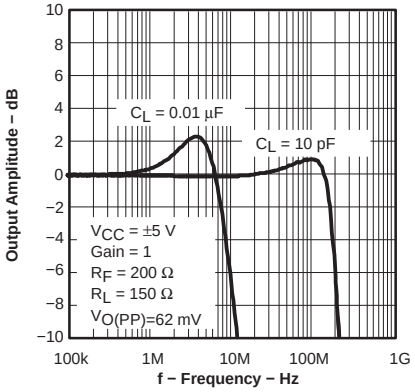


Figure 11

TYPICAL CHARACTERISTICS

OUTPUT AMPLITUDE vs FREQUENCY

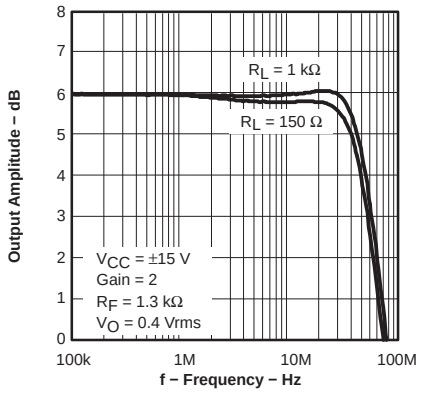


Figure 12

OUTPUT AMPLITUDE vs FREQUENCY

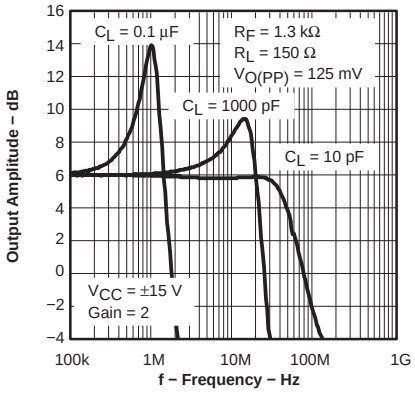


Figure 13

OUTPUT AMPLITUDE vs FREQUENCY

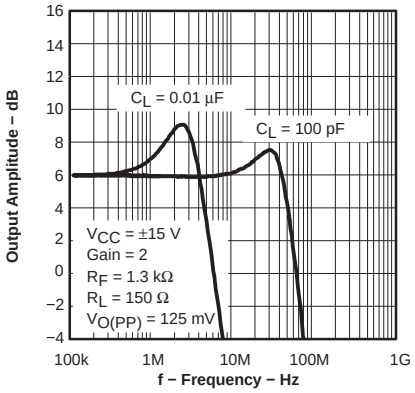


Figure 14

OUTPUT AMPLITUDE vs FREQUENCY

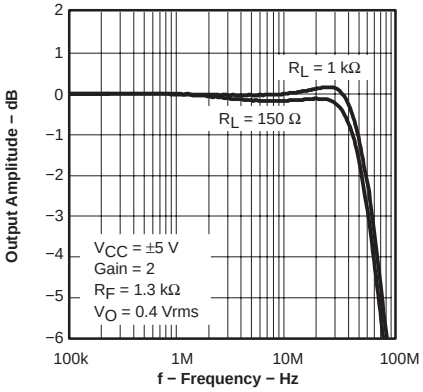


Figure 15

OUTPUT AMPLITUDE vs FREQUENCY

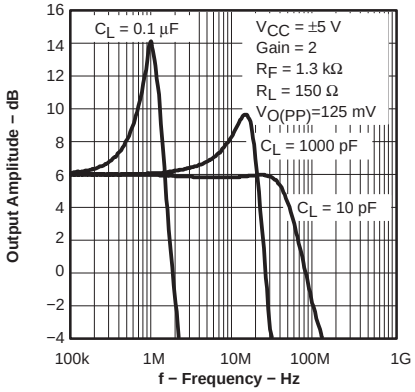


Figure 16

OUTPUT AMPLITUDE vs FREQUENCY

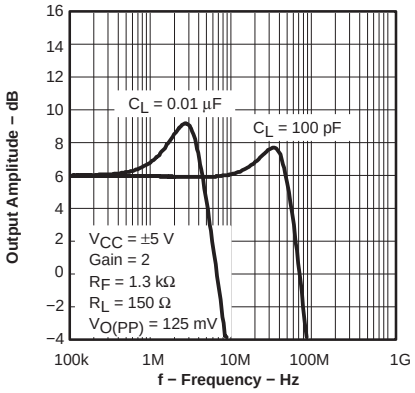


Figure 17

OUTPUT AMPLITUDE vs FREQUENCY

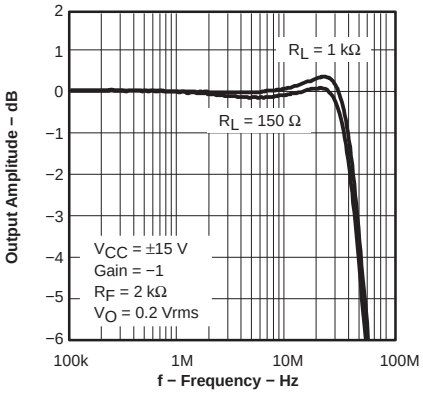


Figure 18

OUTPUT AMPLITUDE vs FREQUENCY

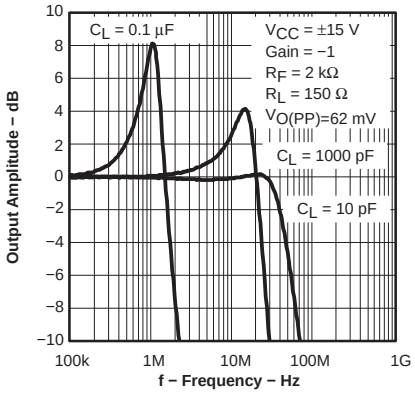


Figure 19

OUTPUT AMPLITUDE vs FREQUENCY

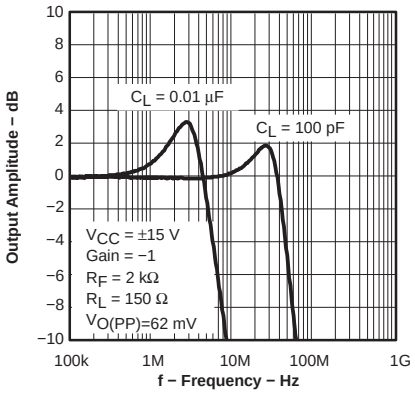


Figure 20

TYPICAL CHARACTERISTICS

OUTPUT AMPLITUDE vs FREQUENCY

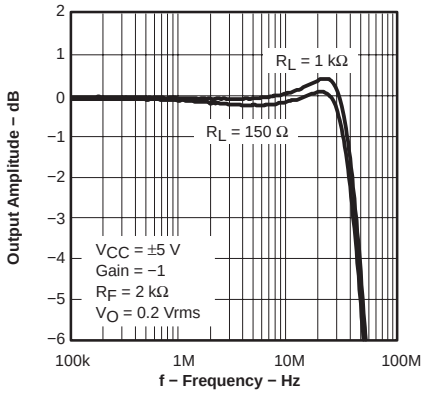


Figure 21

OUTPUT AMPLITUDE vs FREQUENCY

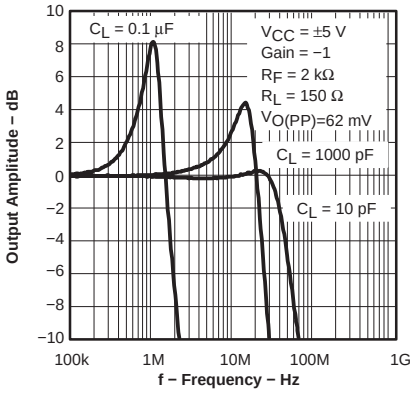


Figure 22

OUTPUT AMPLITUDE vs FREQUENCY

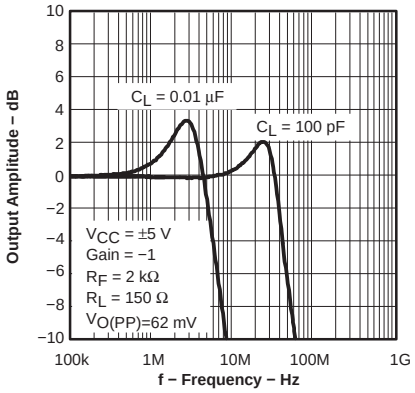


Figure 23

OUTPUT OVERSHOOT vs CAPACITIVE LOAD

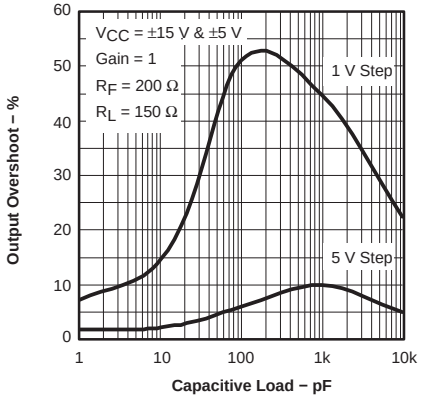


Figure 24

OUTPUT OVERSHOOT vs CAPACITIVE LOAD

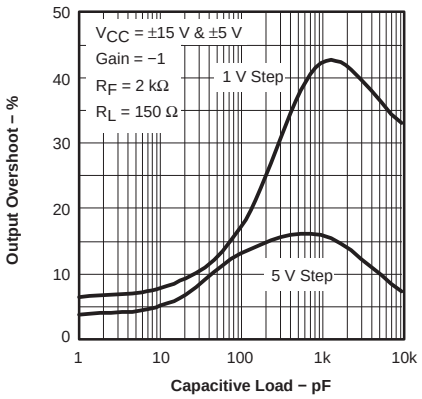


Figure 25

TOTAL HARMONIC DISTORTION vs FREQUENCY

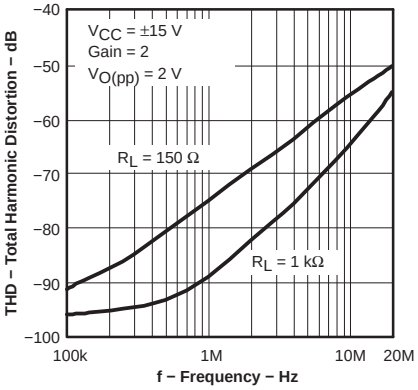


Figure 26

DISTORTION vs FREQUENCY

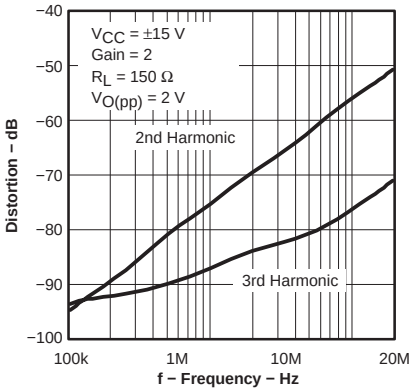


Figure 27

DISTORTION vs FREQUENCY

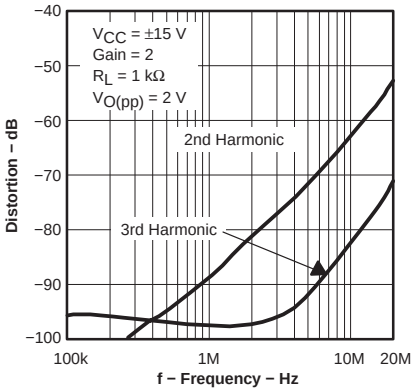


Figure 28

DISTORTION vs FREQUENCY

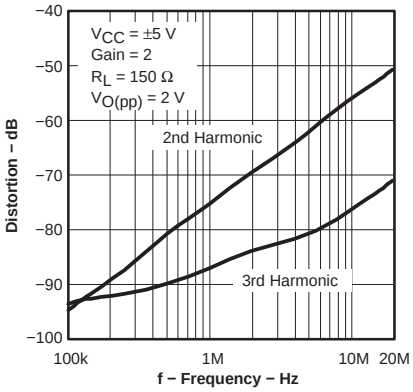


Figure 29

TYPICAL CHARACTERISTICS

DISTORTION vs FREQUENCY

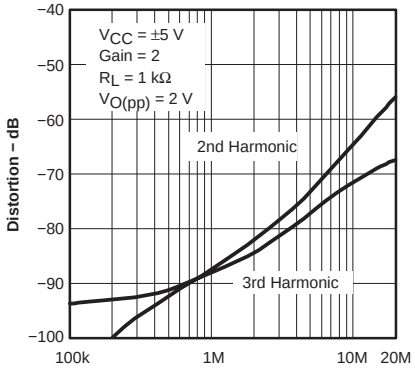


Figure 30

DISTORTION vs OUTPUT VOLTAGE

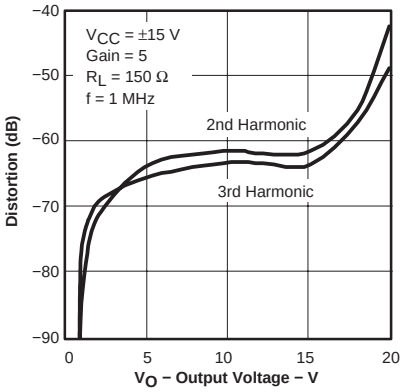


Figure 31

DISTORTION vs OUTPUT VOLTAGE

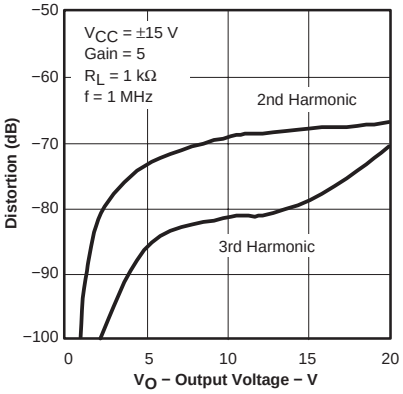


Figure 32

DIFFERENTIAL GAIN vs NUMBER OF 150-Ω LOADS

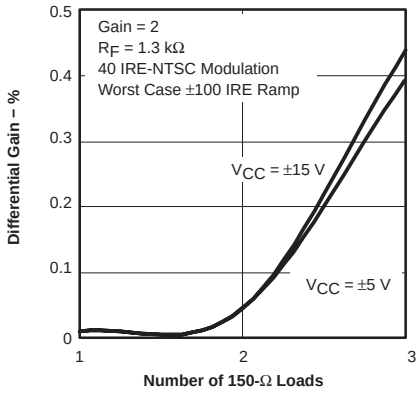


Figure 33

DIFFERENTIAL PHASE vs NUMBER OF 150-Ω LOADS

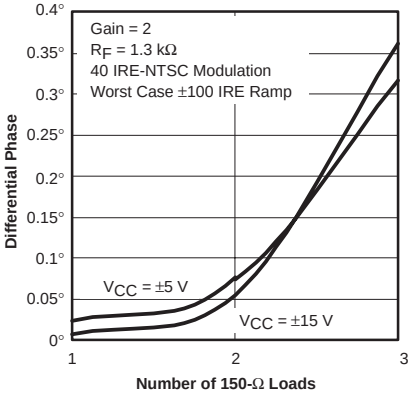


Figure 34

DIFFERENTIAL GAIN vs NUMBER OF 150-Ω LOADS

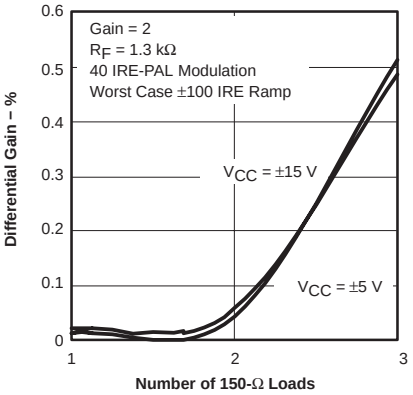


Figure 35

DIFFERENTIAL PHASE vs NUMBER OF 150-Ω LOADS

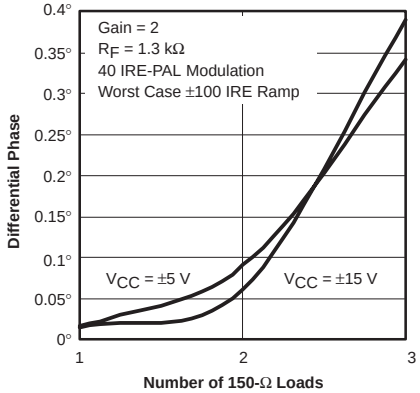


Figure 36

CLOSED-LOOP OUTPUT IMPEDANCE vs FREQUENCY

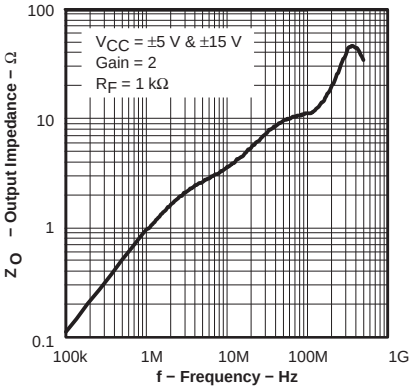


Figure 37

PSRR vs FREQUENCY

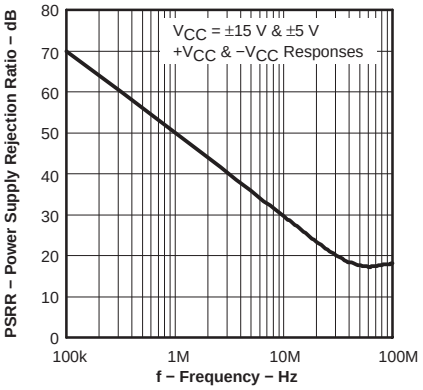


Figure 38

TYPICAL CHARACTERISTICS

CMRR vs FREQUENCY

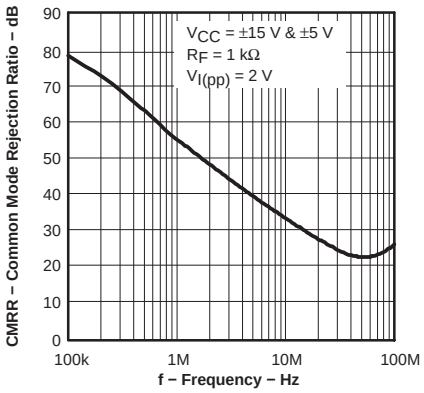


Figure 39

CROSSTALK vs FREQUENCY

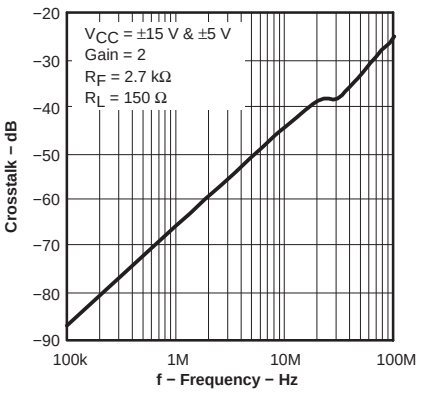


Figure 40

VOLTAGE & CURRENT NOISE vs FREQUENCY

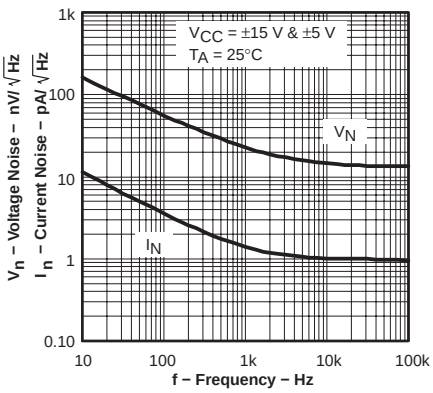


Figure 41

SLEW RATE vs FREE-AIR TEMPERATURE

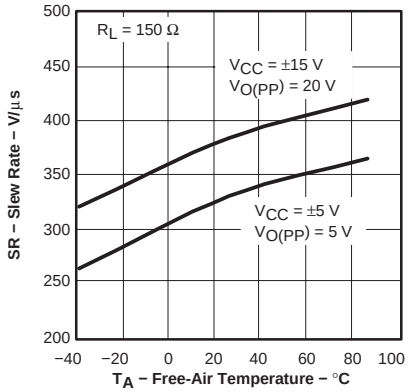


Figure 42

SETTING TIME vs OUTPUT STEP

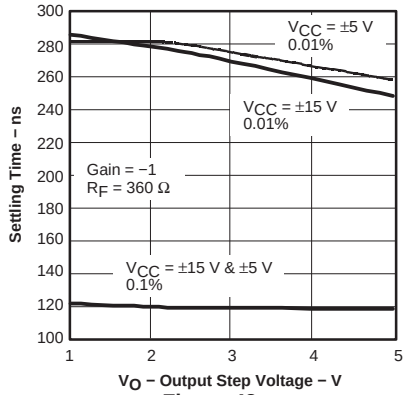


Figure 43

INPUT OFFSET VOLTAGE vs FREE-AIR TEMPERATURE

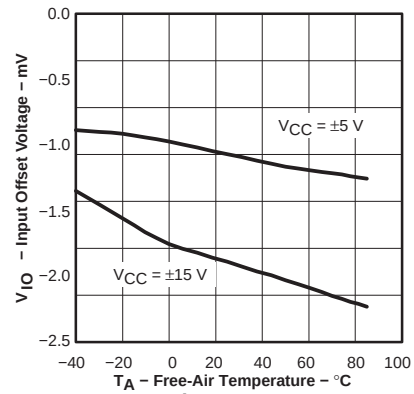


Figure 44

INPUT BIAS CURRENT vs FREE-AIR TEMPERATURE

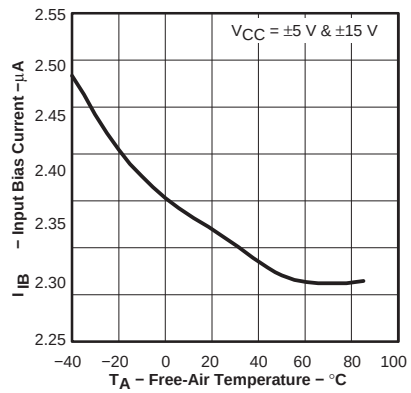


Figure 45

COMMON-MODE INPUT VOLTAGE vs SUPPLY VOLTAGE

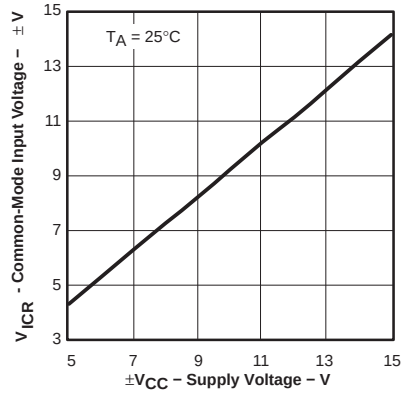


Figure 46

OUTPUT VOLTAGE vs SUPPLY VOLTAGE

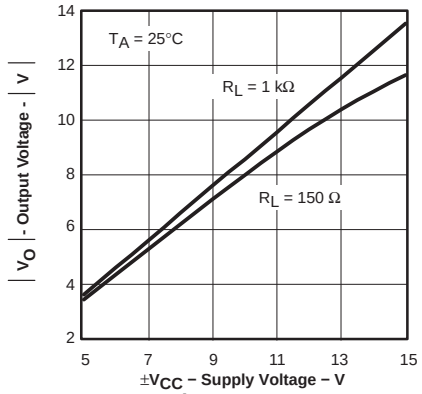


Figure 47

TYPICAL CHARACTERISTICS

OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE

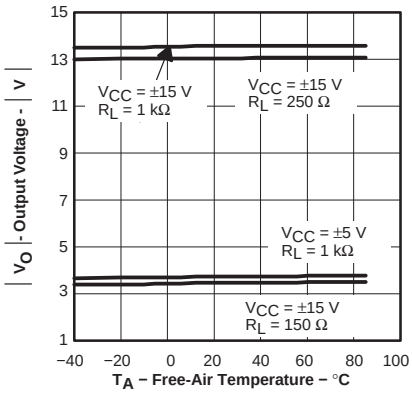


Figure 48

SUPPLY CURRENT vs SUPPLY VOLTAGE

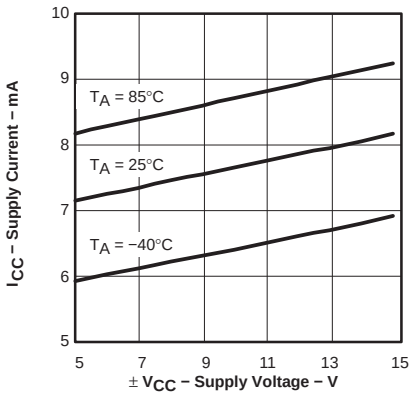


Figure 49

1-V FALLING EDGE RESPONSE

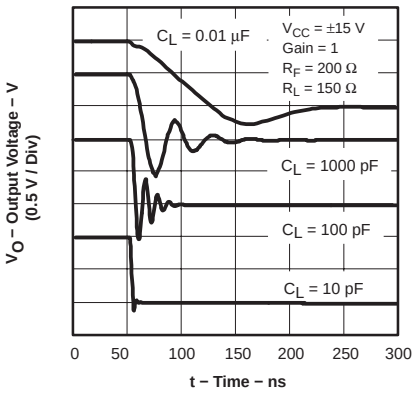


Figure 50

1-V FALLING EDGE RESPONSE

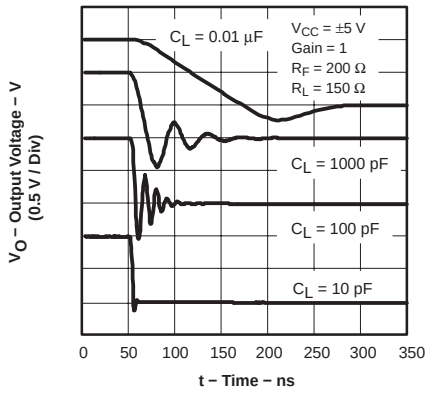


Figure 51

5-V FALLING EDGE RESPONSE

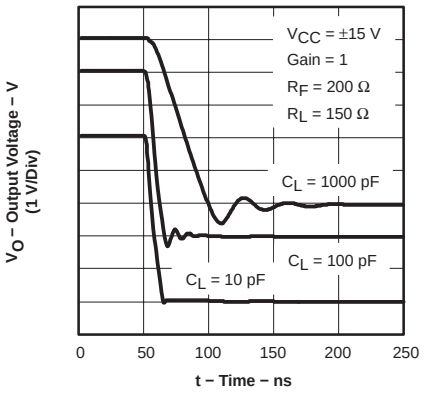


Figure 52

5-V FALLING EDGE RESPONSE

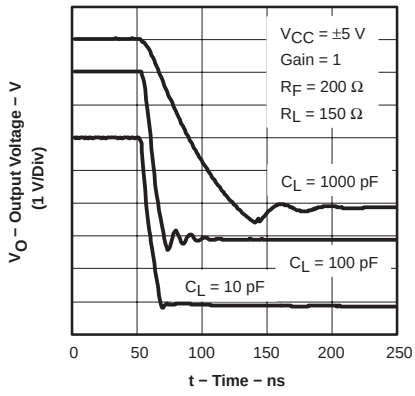


Figure 53

5-V AND 1-V STEP RESPONSE

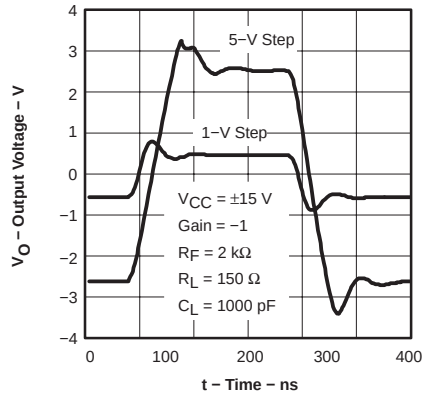


Figure 54

5-V AND 1-V STEP RESPONSE

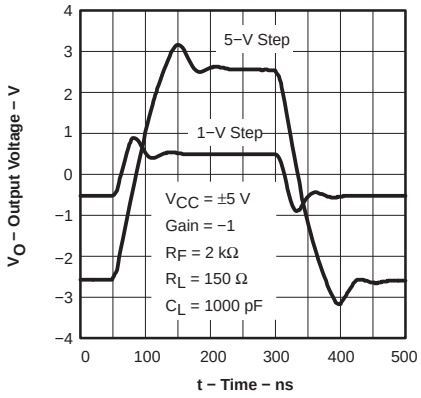


Figure 55

CAPACITIVE LOAD RESPONSE

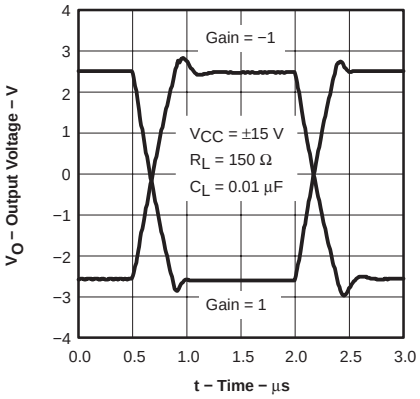


Figure 56

TYPICAL CHARACTERISTICS

CAPACITIVE LOAD RESPONSE

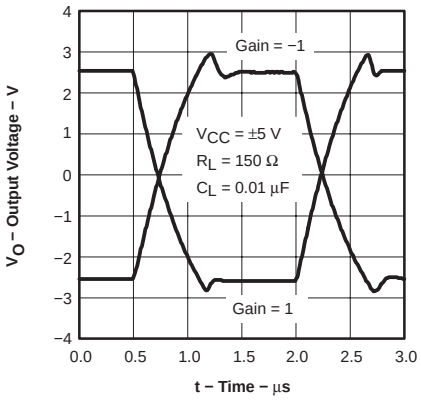


Figure 57

1-V STEP RESPONSE

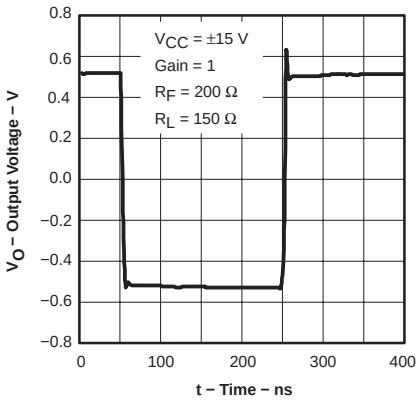


Figure 58

1-V STEP RESPONSE

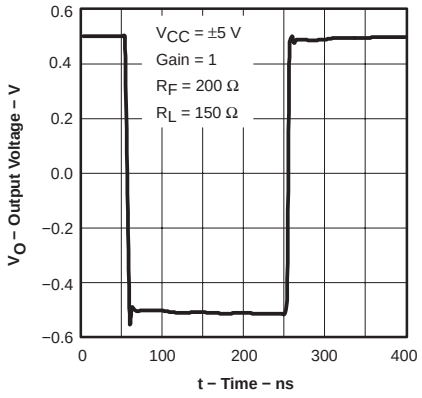


Figure 59

20-V STEP RESPONSE

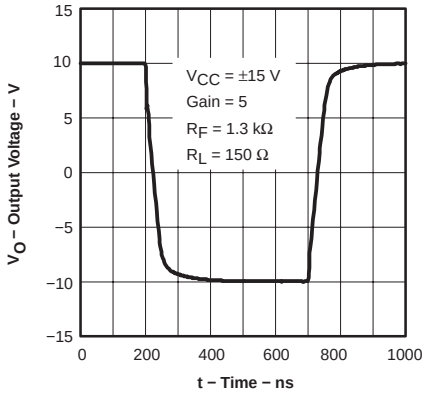


Figure 60

5-V STEP RESPONSE

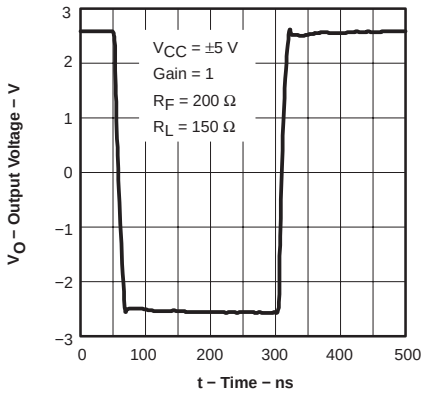


Figure 61

APPLICATION INFORMATION

theory of operation

The THS404x is a high-speed, operational amplifier configured in a voltage feedback architecture. It is built using a 30-V, dielectrically isolated, complementary bipolar process with NPN and PNP transistors possessing f_Ts of several GHz. This results in an exceptionally high performance amplifier that has a wide bandwidth, high slew rate, fast settling time, and low distortion. A simplified schematic is shown in Figure 62.

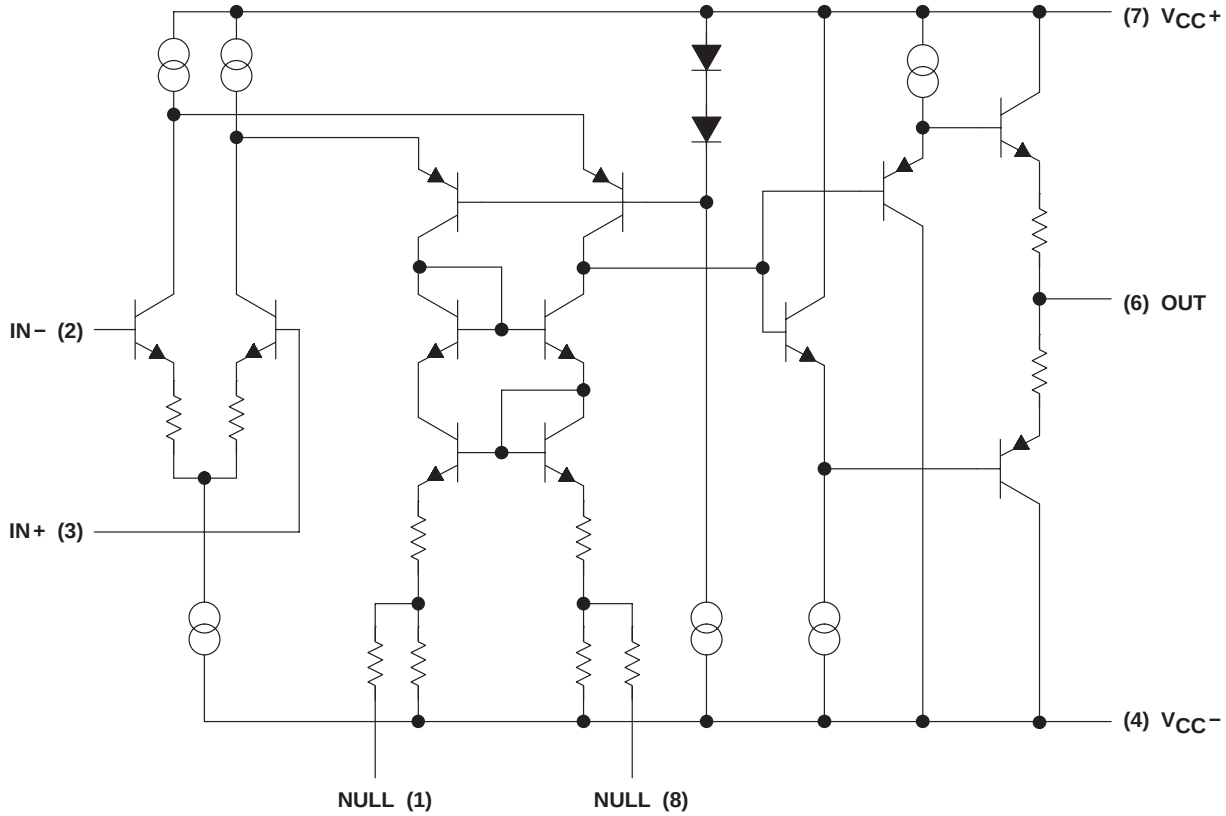


Figure 62. THS4041 Simplified Schematic

noise calculations and noise figure

Noise can cause errors on small signals. This is especially true when amplifying small signals, where signal-to-noise ration (SNR) is important. The noise model for the THS404x is shown in Figure 63. This model includes all of the noise sources as follows:

- e_n = Amplifier internal voltage noise (nV/$\sqrt{Hz}$)
- IN+ = Noninverting current noise (pA/$\sqrt{Hz}$)
- IN− = Inverting current noise (pA/$\sqrt{Hz}$)
- e_{Rx} = Thermal voltage noise associated with each resistor (e_{Rx} = 4 kTR_x)

APPLICATION INFORMATION

noise calculations and noise figure (continued)

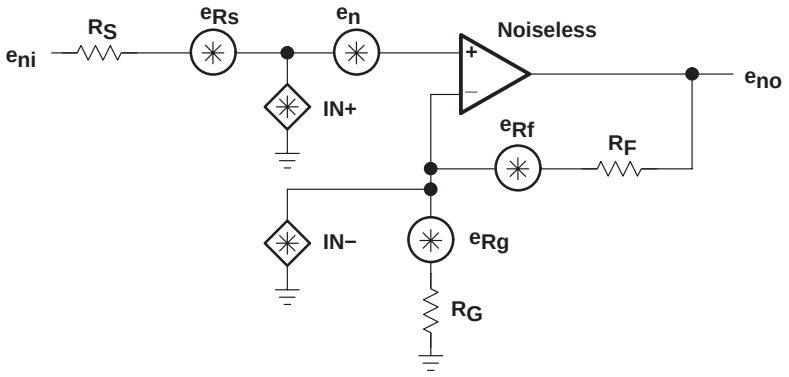


Figure 63. Noise Model

The total equivalent input noise density (e_{ni}) is calculated by using the following equation:

$$e_{ni} = \sqrt{(e_n)^2 + \left(IN + \times R_S\right)^2 + \left(IN- \times \left(R_F \parallel R_G\right)\right)^2 + 4\,kTR_S + 4\,kT\left(R_F \parallel R_G\right)}$$

Where:

k = Boltzmann's constant = 1.380658×10^{-23}
T = Temperature in degrees Kelvin (273 +°C)
$R_F \parallel R_G$ = Parallel resistance of R_F and R_G

To get the equivalent output noise of the amplifier, just multiply the equivalent input noise density (e_{ni}) by the overall amplifier gain (A_V).

$$e_{no} = e_{ni}\,A_V = e_{ni}\left(1 + \frac{R_F}{R_G}\right) \text{ (noninverting case)}$$

As the previous equations show, to keep noise at a minimum, small value resistors should be used. As the closed-loop gain is increased (by reducing R_G), the input noise is reduced considerably because of the parallel resistance term. This leads to the general conclusion that the most dominant noise sources are the source resistor (R_S) and the internal amplifier noise voltage (e_n). Because noise is summed in a root-mean-squares method, noise sources smaller than 25% of the largest noise source can be effectively ignored. This can greatly simplify the formula and make noise calculations much easier to calculate.

For more information on noise analysis, see the *Noise Analysis* section in the *Operational Amplifier Circuits Applications Report* (literature number SLVA043).

APPLICATION INFORMATION

noise calculations and noise figure (continued)

This brings up another noise measurement usually preferred in RF applications, the noise figure (NF). The noise figure is a measure of noise degradation caused by the amplifier. The value of the source resistance must be defined and is typically 50 Ω in RF applications.

$$NF = 10\log\left[\frac{e_{ni}^{2}}{\left(e_{Rs}\right)^{2}}\right]$$

Because the dominant noise components are generally the source resistance and the internal amplifier noise voltage, we can approximate noise figure as:

$$NF = 10\log\left[1 + \frac{\left(\left(e_{n}\right)^{2} + \left(IN + \times R_{S}\right)^{2}\right)}{4\ kTR_{S}}\right]$$

Figure 64 shows the noise figure graph for the THS404x.

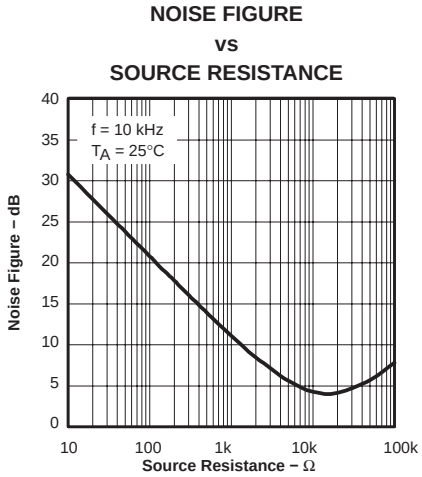


Figure 64.

APPLICATION INFORMATION

driving a capacitive load

Driving capacitive loads with high performance amplifiers is not a problem as long as certain precautions are taken. The first is to realize that the THS404x has been internally compensated to maximize its bandwidth and slew rate performance. Typically when the amplifier is compensated in this manner, capacitive loading directly on the output will decrease the device's phase margin, leading to high frequency ringing or oscillations. However, the THS404x has added internal circuitry that senses a capacitive load and adds extra compensation to the internal dominant pole. As the capacitive load increases, the amplifier remains stable. But, it is not uncommon to see a small amount of peaking in the frequency response. There are typically two ways to compensate for this. The first is to simply increase the gain of the amplifier. This helps by increasing the phase margin to keep peaking minimized. The second is to place an isolation resistor in series with the output of the amplifier, as shown in Figure 65. A minimum value of 20 Ω should work well for most applications. For example, in 75-Ω transmission systems, setting the series resistor value to 75 Ω both isolates any capacitance loading and provides the proper line impedance matching at the source end. For more information about driving capacitive loads, see the *Output Resistance and Capacitance* section of the *Parasitic Capacitance in Op Amp Circuits Application Report* (literature number SLOA013).

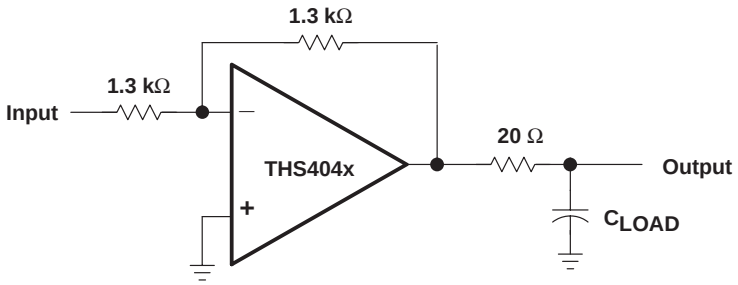


Figure 65. Driving a Capacitive Load for Extra Stability

offset nulling

The THS404x has low input offset voltage for a high-speed amplifier. However, if additional correction is required, an offset nulling function has been provided on the THS4041. The input offset can be adjusted by placing a potentiometer between terminals 1 and 8 of the device and tying the wiper to the negative supply. This is shown in Figure 66.

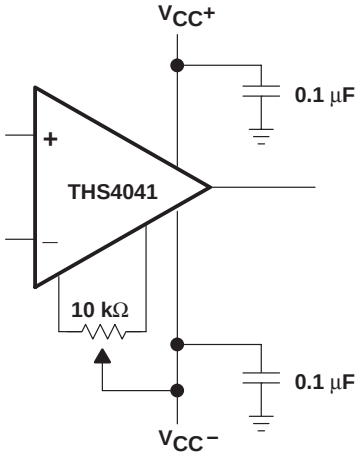
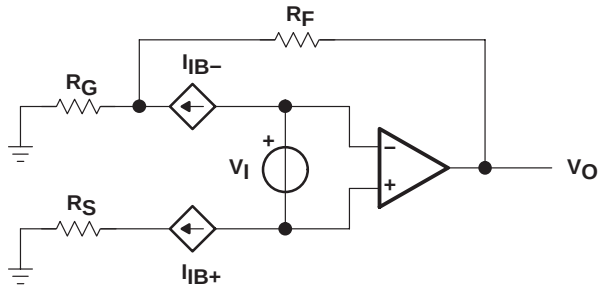


Figure 66. Offset Nulling Schematic

APPLICATION INFORMATION

offset voltage

The output offset voltage, (V_{OO}) is the sum of the input offset voltage (V_{IO}) and both input bias currents (I_{IB}) times the corresponding gains. The following schematic and formula can be used to calculate the output offset voltage:



$$V_{OO} = V_{IO}\left(1 + \left(\frac{R_F}{R_G}\right)\right) \pm I_{IB+} R_S \left(1 + \left(\frac{R_F}{R_G}\right)\right) \pm I_{IB-} R_F$$

Figure 67. Output Offset Voltage Model

optimizing unity gain response

Internal frequency compensation of the THS404x was selected to provide very wideband performance yet still maintain stability when operated in a noninverting unity gain configuration. When amplifiers are compensated in this manner there is usually peaking in the closed loop response and some ringing in the step response for fast input edges, depending upon the application. This is because a minimum phase margin is maintained for the G=+1 configuration. For optimum settling time and minimum ringing, a feedback resistor of 200 Ω should be used as shown in Figure 68. Additional capacitance can also be used in parallel with the feedback resistance if even finer optimization is required.

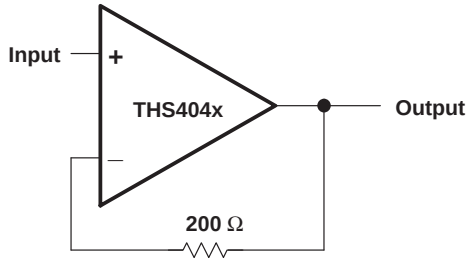


Figure 68. Noninverting, Unity Gain Schematic

APPLICATION INFORMATION

circuit layout considerations

To achieve the levels of high frequency performance of the THS404x, follow proper printed-circuit board high frequency design techniques. A general set of guidelines is given below. In addition, a THS404x evaluation board is available to use as a guide for layout or for evaluating the device performance.

- Ground planes − It is highly recommended that a ground plane be used on the board to provide all components with a low inductive ground connection. However, in the areas of the amplifier inputs and output, the ground plane can be removed to minimize the stray capacitance.
- Proper power supply decoupling − Use a 6.8-μF tantalum capacitor in parallel with a 0.1-μF ceramic capacitor on each supply terminal. It may be possible to share the tantalum among several amplifiers depending on the application, but a 0.1-μF ceramic capacitor should always be used on the supply terminal of every amplifier. In addition, the 0.1-μF capacitor should be placed as close as possible to the supply terminal. As this distance increases, the inductance in the connecting trace makes the capacitor less effective. The designer should strive for distances of less than 0.1 inches between the device power terminals and the ceramic capacitors.
- Sockets − Sockets are not recommended for high-speed operational amplifiers. The additional lead inductance in the socket pins often leads to stability problems. Surface-mount packages soldered directly to the printed-circuit board is the best implementation.
- Short trace runs/compact part placements − Optimum high frequency performance is achieved when stray series inductance has been minimized. To realize this, the circuit layout should be made as compact as possible, thereby minimizing the length of all trace runs. Particular attention should be paid to the inverting input of the amplifier. Its length should be kept as short as possible. This helps to minimize stray capacitance at the input of the amplifier.
- Surface-mount passive components − Using surface-mount passive components is recommended for high frequency amplifier circuits for several reasons. First, because of the extremely low lead inductance of surface-mount components, the problem with stray series inductance is greatly reduced. Second, the small size of surface-mount components naturally leads to a more compact layout, thereby minimizing both stray inductance and capacitance. If leaded components are used, it is recommended that the lead lengths be kept as short as possible.

APPLICATION INFORMATION

evaluation board

An evaluation board is available for the THS4041 (literature number SLOP219). This board has been configured for very low parasitic capacitance in order to realize the full performance of the amplifier. A schematic of the evaluation board is shown in Figure 69. The circuitry has been designed so that the amplifier may be used in either an inverting or noninverting configuration. For more information, see the *THS4041 EVM User's Guide*. To order the evaluation board, contact your local Texas Instruments sales office or distributor.

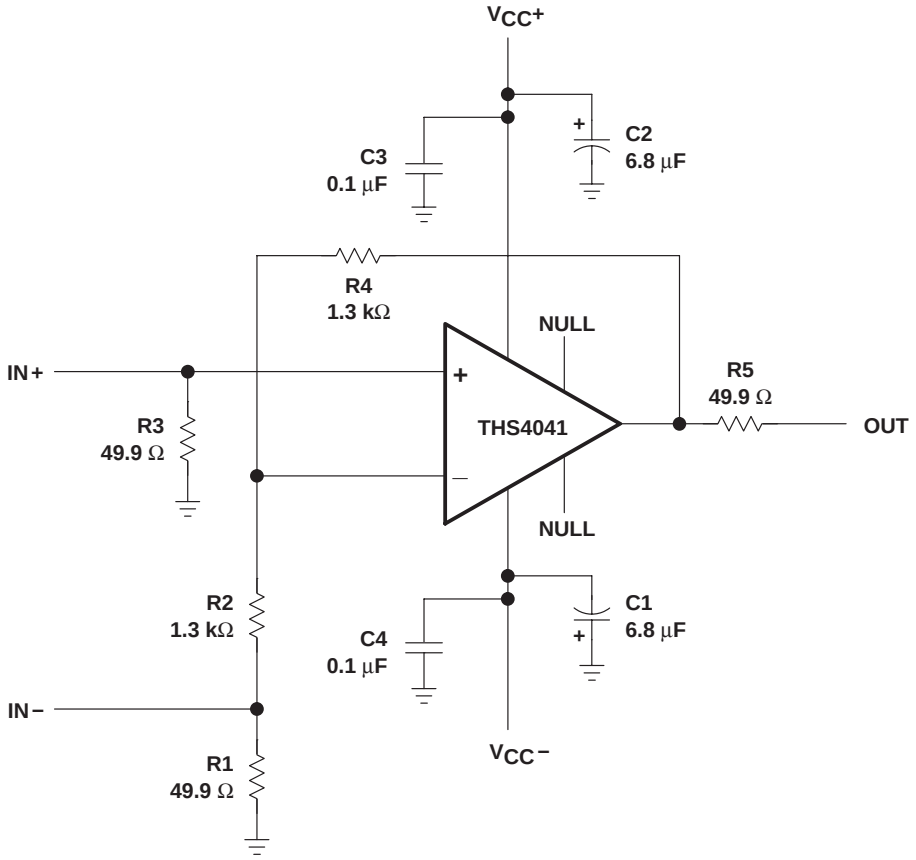


Figure 69. THS4041 Evaluation Board

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
THS4041IDRQ1	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	4041Q1
THS4041IDRQ1.A	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	4041Q1

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

OTHER QUALIFIED VERSIONS OF THS4041-Q1 :

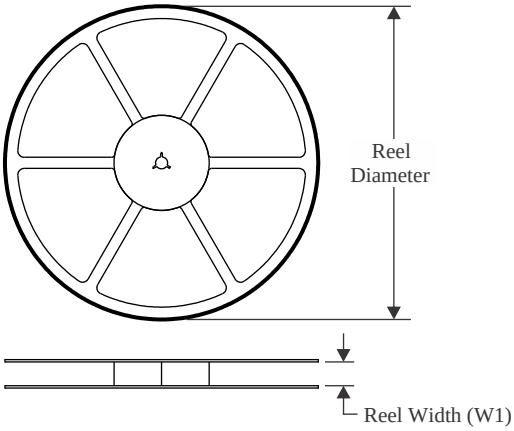
- Catalog : THS4041

NOTE: Qualified Version Definitions:

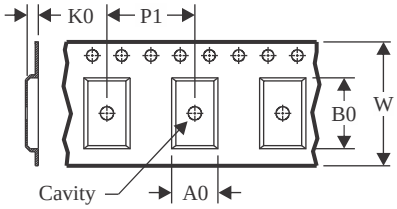
- Catalog - TI's standard catalog product

TAPE AND REEL INFORMATION

REEL DIMENSIONS

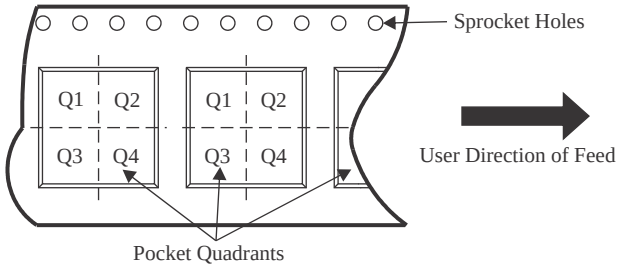


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

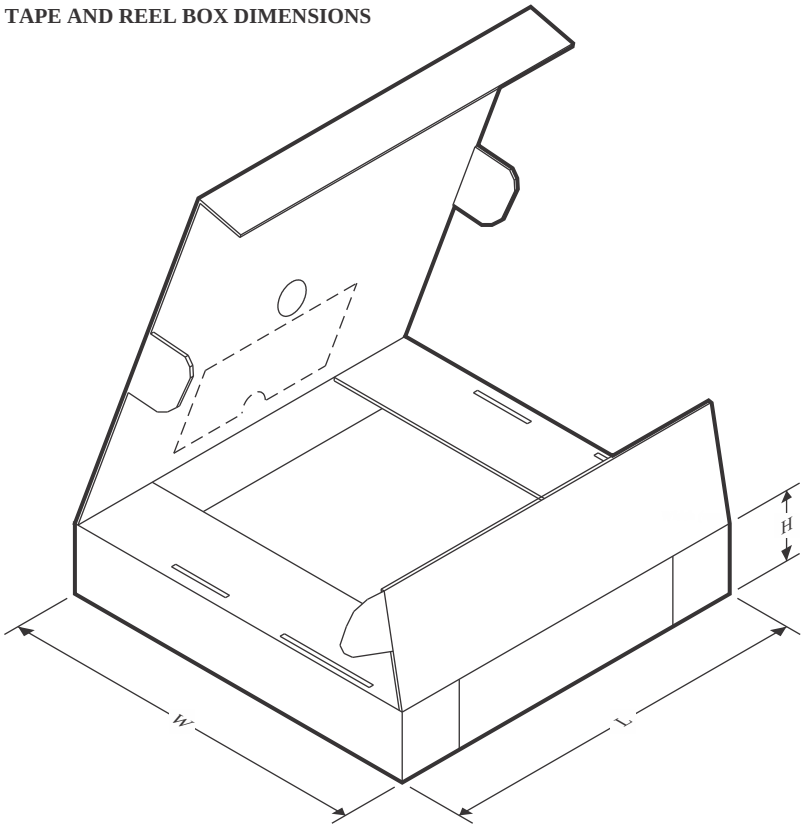
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

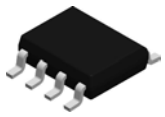
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THS4041IDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THS4041IDRQ1	SOIC	D	8	2500	350.0	350.0	43.0

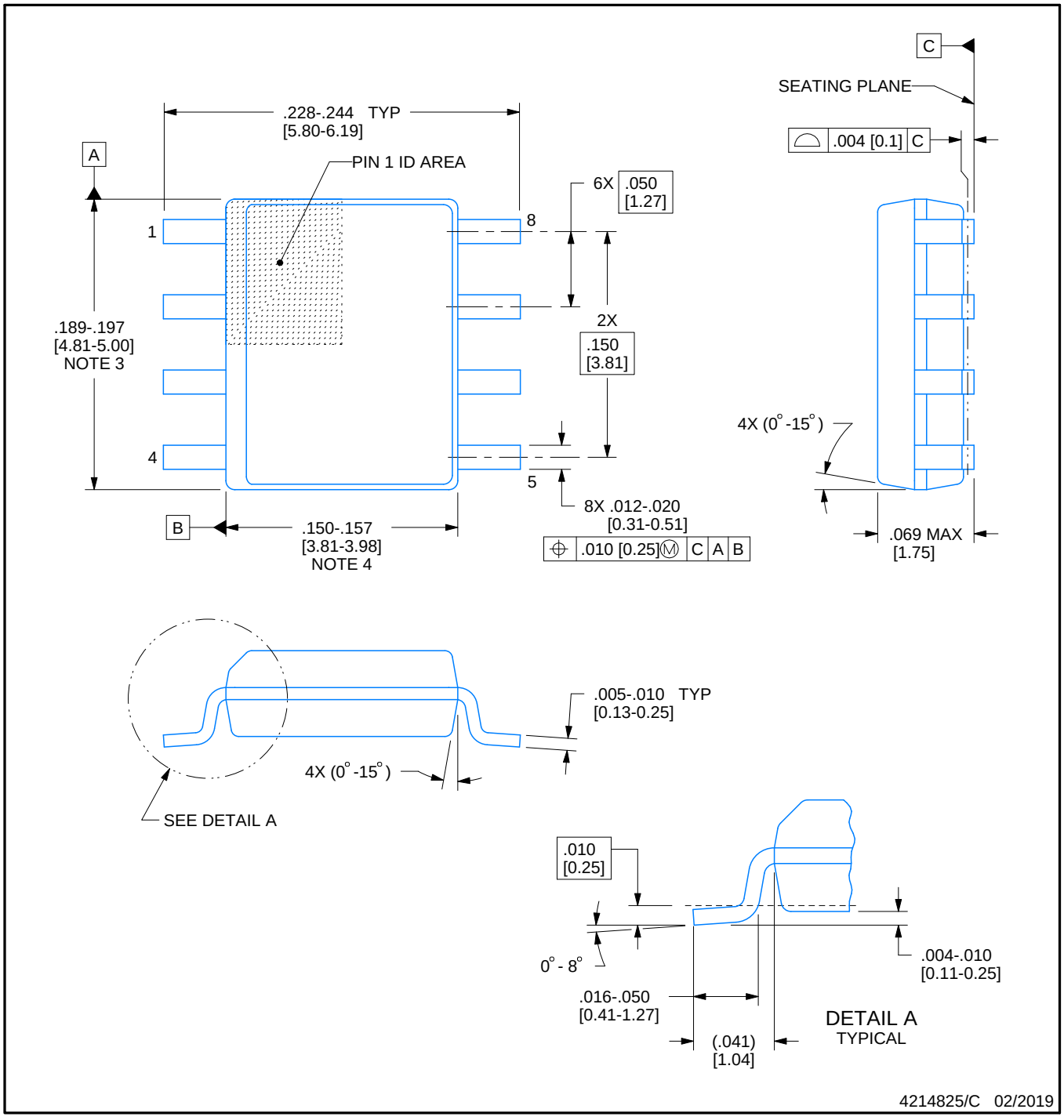


PACKAGE OUTLINE

D0008A

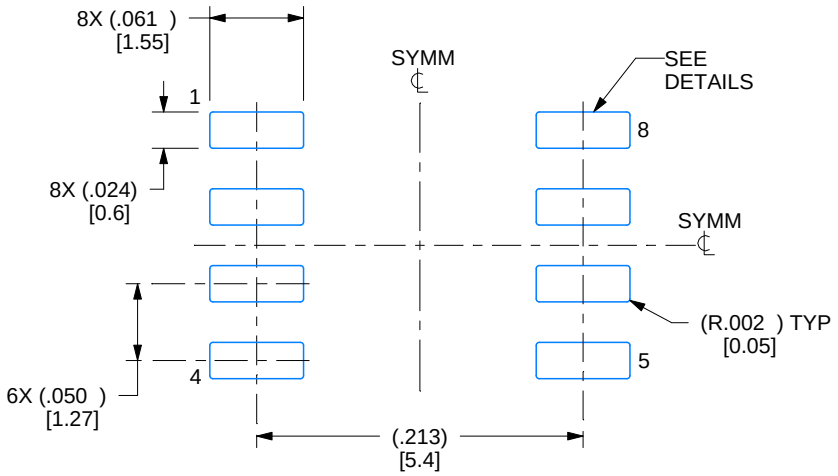
SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

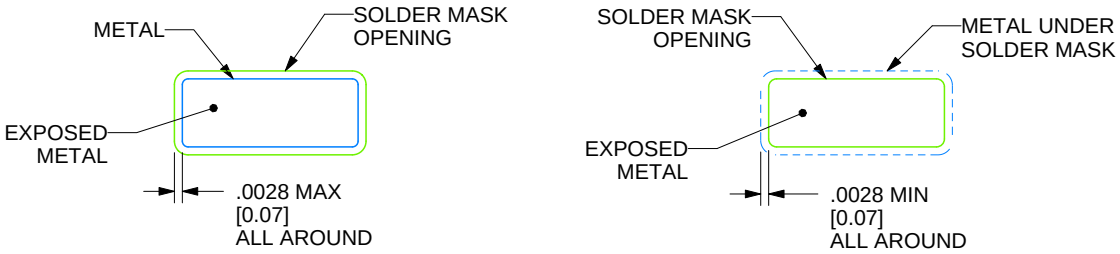


NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

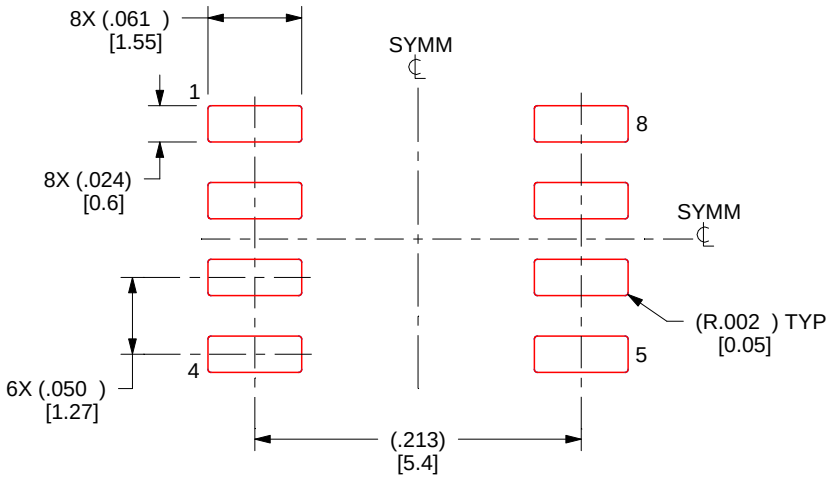
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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